

JAP20 Rec'd 10 CTM 26 APR 2006

FORM PTO-1449	SERIAL NO. <del>Not Yet Assigned</del>	CASE NO. 401577175 9905/40 (BIF115433/US)
<b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b>	FILING DATE Herewith	GROUP ART UNIT <del>Not Yet Assigned</del>
APPLICANTS: NGUYEN et al.		

**REFERENCE DESIGNATION**      **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	A1 US 2004/0144487 A1	07/29/2004	Martinez et al.		
	A2 US 2003/0134489 A1	07/17/2003	Schwarzenbach et al.		
	A3 US 2003/0077885 A1	04/24/2003	Aspar et al.		
	A4 US 2002/0025604 A1	02/28/2003	Tiwari		
	A5 US 6,593,212 B1	07/15/2003	Kub et al.		
	A6 US 6,362,077 B1	03/26/2002	Aspar et al.		
	A7 US 6,303,468 B1	10/16/2001	Aspar et al.		
	A8 US 6,225,192	05/01/2001	Aspar et al.		
	A9 US 6,020,252	02/01/2000	Aspar et al.		

## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO	
	A10 FR 2 847 075 A1	05/14/2004	France		Abstract	
	A11 FR 2 767 416 A1	02/19/1999	France		Abstract	
	A12 WO 2004/044976 A1	05/27/2004	PCT		Abstract	
	A13 WO 03/013815 A1	02/20/2003	PCT		Abstract	
	A14 WO 02/083387 A1	10/24/2002	PCT		Abstract	
	A15 WO 00/63965	10/26/2000	PCT			
	A16 EP 0 994 503 A1	04/19/2000	EPO		Abstract	
	A17 EP 02 293 049 A1	05/20/1988	EPO			
	A18 EP 02 293 049 B1	05/20/1988	EPO			

EXAMINER INITIAL	OTHER ART – NON PATENT LITERATURE DOCUMENTS (Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.)	
	A19	Argawal et al., "Efficient Production of Silicon-on-Insulator Films by Co-Implantation of He+ with H+," <i>Applied Physics Letters</i> , Volume 72, Number 9, 2 March 1998 ; pp. 1086-1088.
	A20	Cerofolini et al., <i>Materials Science and Engineering</i> , B71 - 2000, pp. 196-202.
	A21	Henttinen et al., <i>Applied Physics Letters</i> , Volume 16, Number 17, 24 April 2000; pp. 2370-2372.

EXAMINER	/Daniel Luke/	DATE CONSIDERED	06/15/2009
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with next  
communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /DL/